

Search Notes

Application/Control No.

10/735,971

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

O'DAY, RICHARD F.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	592.1 602.1 603.03 603.04	8/1/2006	PK
	606 607		
360	264.7		
	264.9		
	266.4		
	294.5		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search EAST/NPL (IEEE)	8/1/2006	PK